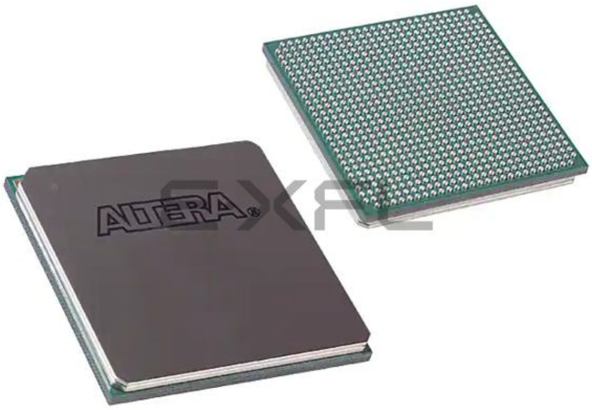

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

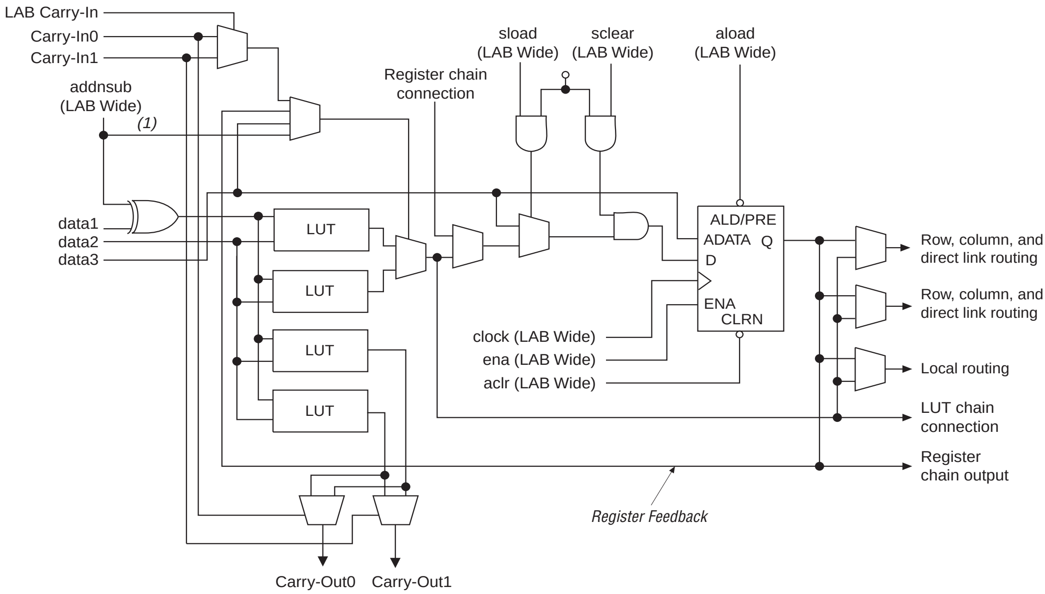
Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	4125
Number of Logic Elements/Cells	41250
Total RAM Bits	3423744
Number of I/O	615
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	780-BBGA, FCBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1s40f780c5n

Figure 2–7. LE in Dynamic Arithmetic Mode



Note to Figure 2–7:

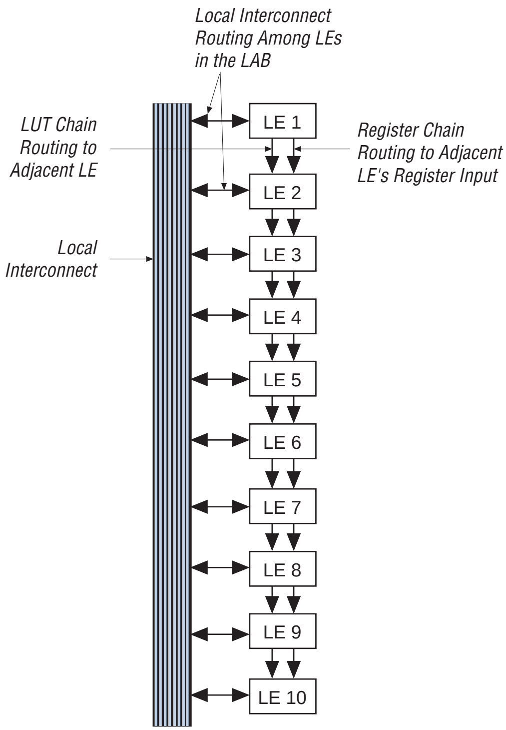
(1) The `addnsub` signal is tied to the carry input for the first LE of a carry chain only.

Carry-Select Chain

The carry-select chain provides a very fast carry-select function between LEs in arithmetic mode. The carry-select chain uses the redundant carry calculation to increase the speed of carry functions. The LE is configured to calculate outputs for a possible carry-in of 1 and carry-in of 0 in parallel. The `carry-in0` and `carry-in1` signals from a lower-order bit feed forward into the higher-order bit via the parallel carry chain and feed into both the LUT and the next portion of the carry chain. Carry-select chains can begin in any LE within an LAB.

The speed advantage of the carry-select chain is in the parallel pre-computation of carry chains. Since the LAB carry-in selects the precomputed carry chain, not every LE is in the critical path. Only the propagation delay between LAB carry-in generation (LE 5 and LE 10) are now part of the critical path. This feature allows the Stratix architecture to implement high-speed counters, adders, multipliers, parity functions, and comparators of arbitrary width.

Figure 2–10. LUT Chain & Register Chain Interconnects



The C4 interconnects span four LABs, M512, or M4K blocks up or down from a source LAB. Every LAB has its own set of C4 interconnects to drive either up or down. Figure 2–11 shows the C4 interconnect connections from an LAB in a column. The C4 interconnects can drive and be driven by all types of architecture blocks, including DSP blocks, TriMatrix memory blocks, and vertical IOEs. For LAB interconnection, a primary LAB or its LAB neighbor can drive a given C4 interconnect. C4 interconnects can drive each other to extend their range as well as drive row interconnects for column-to-column connections.

Figure 2–15. M512 RAM Block Control Signals

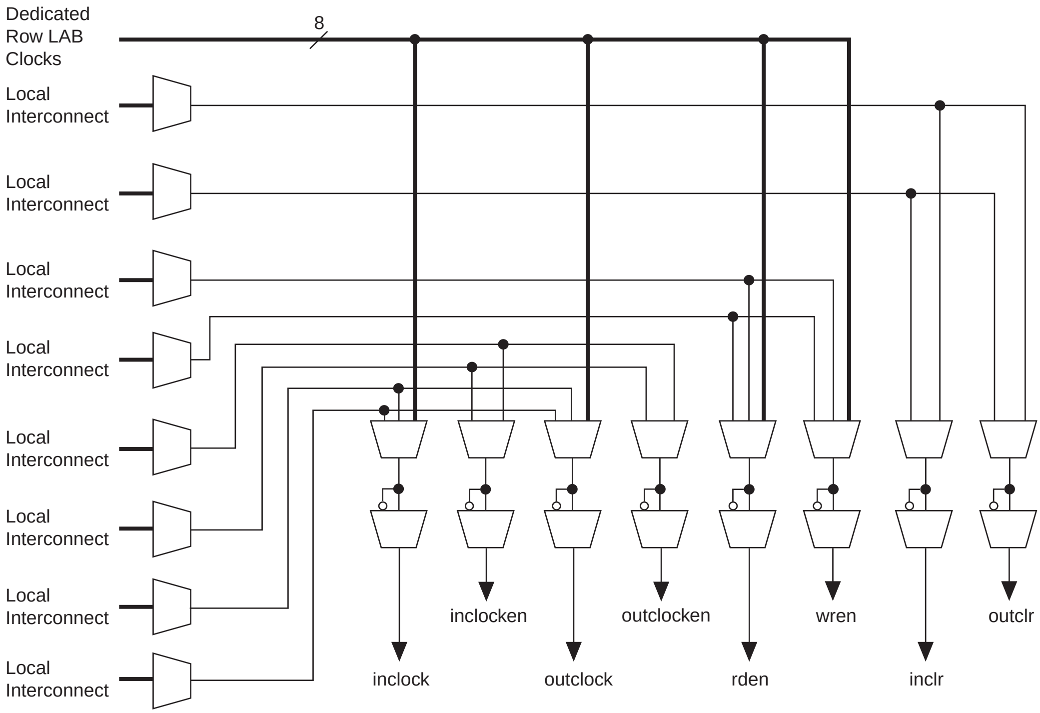
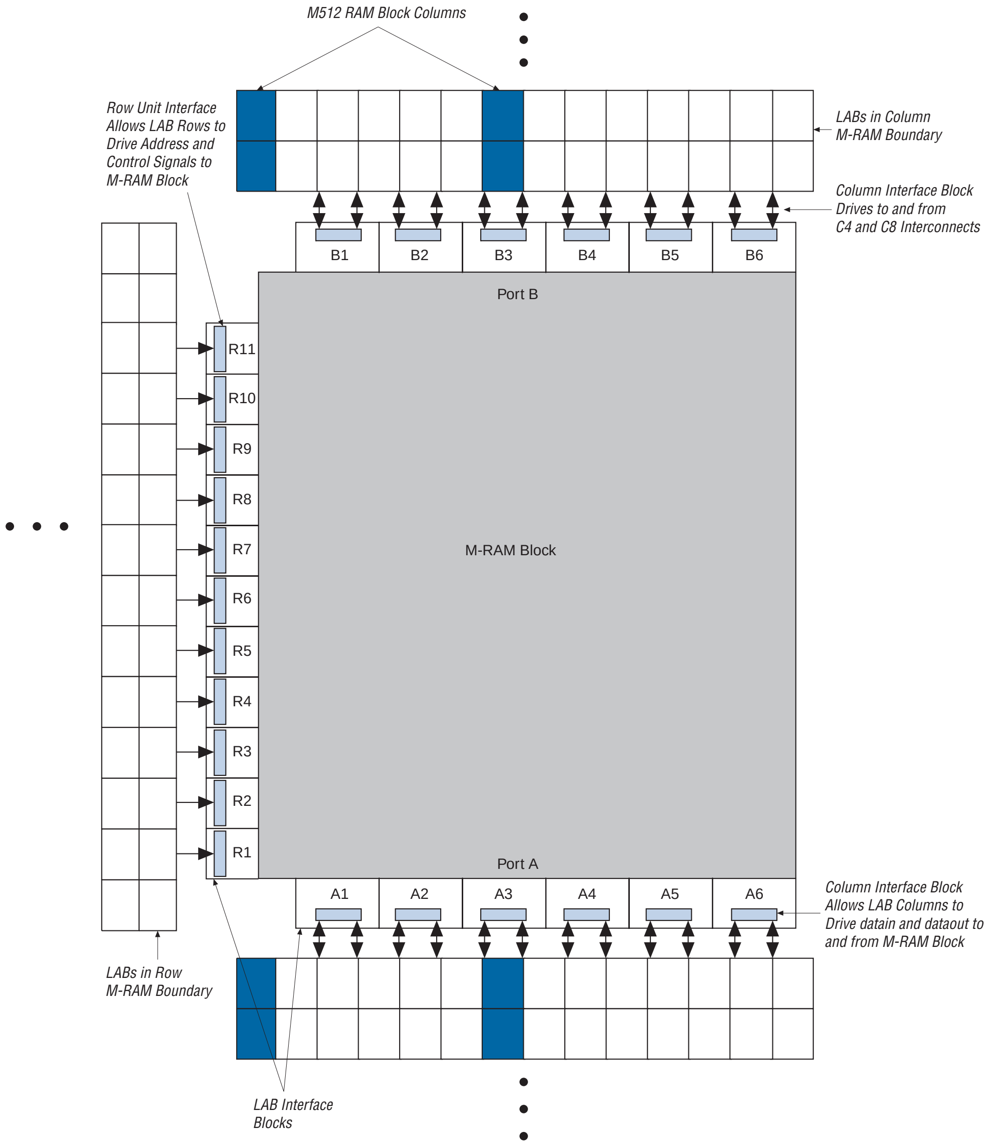


Figure 2–21. Left-Facing M-RAM to Interconnect Interface *Notes (1), (2)*



Notes to Figure 2–21:

(1) Only R24 and C16 interconnects cross the M-RAM block boundaries.

(2) The right-facing M-RAM block has interface blocks on the right side, but none on the left. B1 to B6 and A1 to A6 orientation is clipped across the vertical axis for right-facing M-RAM blocks.

Table 2–14 shows the summary of input register modes for the DSP block.

Table 2–14. Input Register Modes

Register Input Mode	9 × 9	18 × 18	36 × 36
Parallel input	✓	✓	✓
Shift register input	✓	✓	

Multiplier

The multiplier supports 9 × 9-, 18 × 18-, or 36 × 36-bit multiplication. Each DSP block supports eight possible 9 × 9-bit or smaller multipliers. There are four multiplier blocks available for multipliers larger than 9 × 9 bits but smaller than 18 × 18 bits. There is one multiplier block available for multipliers larger than 18 × 18 bits but smaller than or equal to 36 × 36 bits. The ability to have several small multipliers is useful in applications such as video processing. Large multipliers greater than 18 × 18 bits are useful for applications such as the mantissa multiplication of a single-precision floating-point number.

The multiplier operands can be signed or unsigned numbers, where the result is signed if either input is signed as shown in Table 2–15. The `sign_a` and `sign_b` signals provide dynamic control of each operand's representation: a logic 1 indicates the operand is a signed number, a logic 0 indicates the operand is an unsigned number. These sign signals affect all multipliers and adders within a single DSP block and you can register them to match the data path pipeline. The multipliers are full precision (that is, 18 bits for the 18-bit multiply, 36-bits for the 36-bit multiply, and so on) regardless of whether `sign_a` or `sign_b` set the operands as signed or unsigned numbers.

Table 2–15. Multiplier Signed Representation

Data A	Data B	Result
Unsigned	Unsigned	Unsigned
Unsigned	Signed	Signed
Signed	Unsigned	Signed
Signed	Signed	Signed

Output Selection Multiplexer

The outputs from the various elements of the adder/output block are routed through an output selection multiplexer. Based on the DSP block operational mode and user settings, the multiplexer selects whether the output from the multiplier, the adder/subtractor/accumulator, or summation block feeds to the output.

Output Registers

Optional output registers for the DSP block outputs are controlled by four sets of control signals: `clock[3..0]`, `aclr[3..0]`, and `ena[3..0]`. Output registers can be used in any mode.

Modes of Operation

The adder, subtractor, and accumulate functions of a DSP block have four modes of operation:

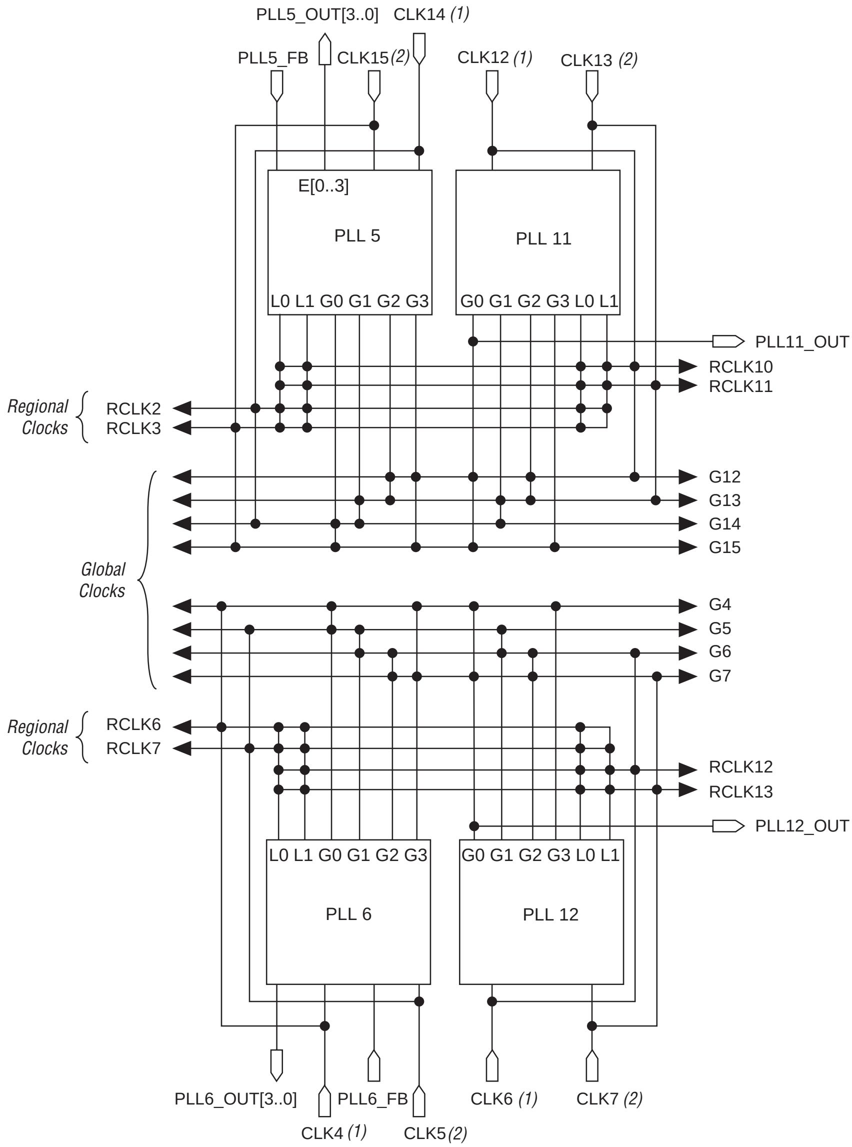
- Simple multiplier
- Multiply-accumulator
- Two-multipliers adder
- Four-multipliers adder

☞ Each DSP block can only support one mode. Mixed modes in the same DSP block is not supported.

Simple Multiplier Mode

In simple multiplier mode, the DSP block drives the multiplier sub-block result directly to the output with or without an output register. Up to four 18 × 18-bit multipliers or eight 9 × 9-bit multipliers can drive their results directly out of one DSP block. See Figure 2–35.

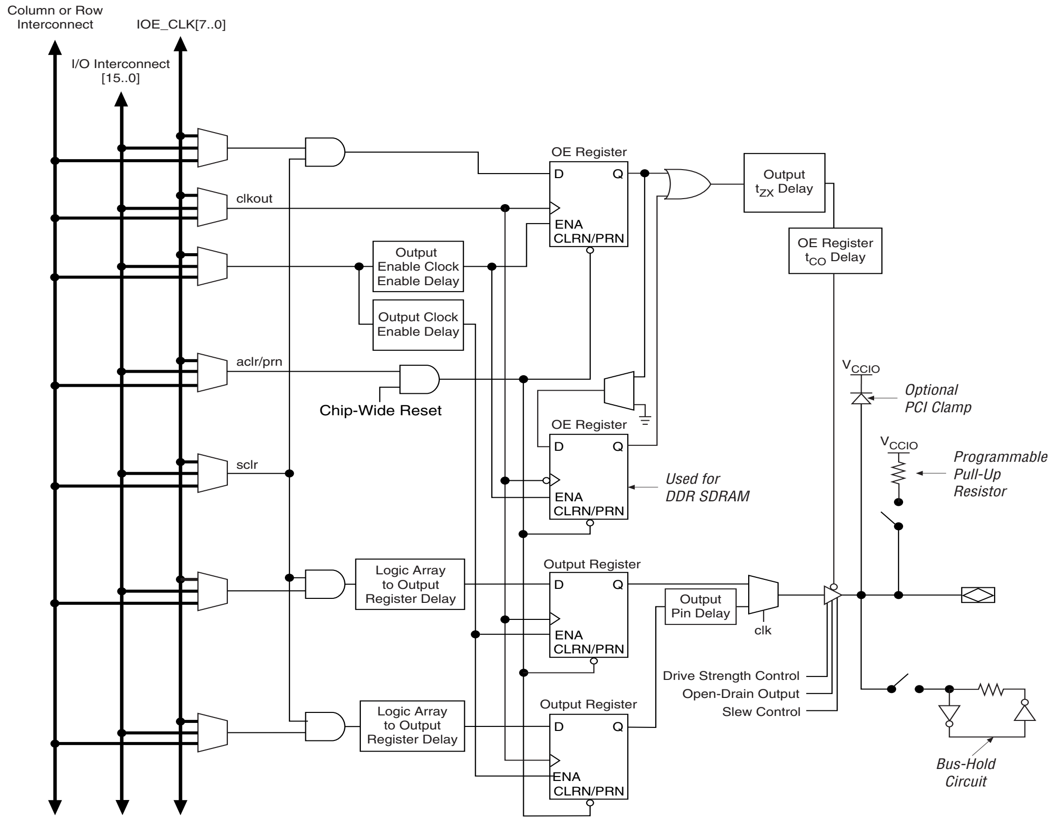
Figure 2–51. Global & Regional Clock Connections from Top Clock Pins & Enhanced PLL Outputs Note (1)



Notes to Figure 2–51:

(1) PLLs 1 to 4 and 7 to 10 are fast PLLs. PLLs 5, 6, 11, and 12 are enhanced PLLs.
(2) `CLK4`, `CLK6`, `CLK12`, and `CLK14` feed the corresponding PLL's `inclk0` port.
(3) `CLK5`, `CLK7`, `CLK13`, and `CLK15` feed the corresponding PLL's `inclk1` port.
(4) The EP1S40 device in the 780-pin FineLine BGA package does not support PLLs 11 and 12.

Figure 2–67. Stratix IOE in DDR Output I/O Configuration Notes (1), (2)



Notes to Figure 2–67:

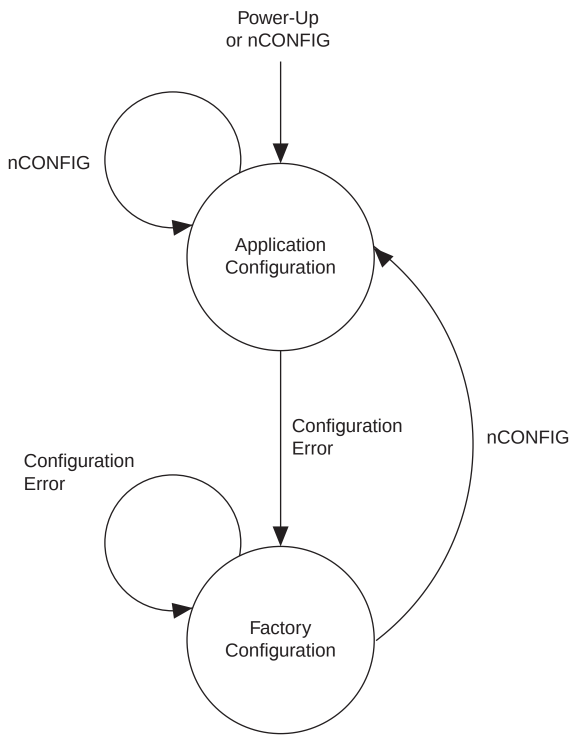
(1) All input signals to the IOE can be inverted at the IOE.

(2) The tristate is by default active high. It can, however, be designed to be active low.

Local Update Mode

Local update mode is a simplified version of the remote update. This feature is intended for simple systems that need to load a single application configuration immediately upon power up without loading the factory configuration first. Local update designs have only one application configuration to load, so it does not require a factory configuration to determine which application configuration to use. Figure 3–4 shows the transition diagram for local update mode.

Figure 3–4. Local Update Transition Diagram



Stratix Automated Single Event Upset (SEU) Detection

Stratix devices offer on-chip circuitry for automated checking of single event upset (SEU) detection. FPGA devices that operate at high elevations or in close proximity to earth's North or South Pole require periodic checks to ensure continued data integrity. The error detection cyclic redundancy check (CRC) feature controlled by the **Device & Pin Options** dialog box in the Quartus II software uses a 32-bit CRC circuit to ensure data reliability and is one of the best options for mitigating SEU.

Table 4–25. 3.3-V AGP 1× Specifications (Part 2 of 2)						
Symbol	**Parameter**	**Conditions**	**Minimum**	**Typical**	**Maximum**	**Unit**
V_{OH}	High-level output voltage	I_{OUT} = –0.5 mA	0.9 × V_{CCIO}		3.6	V
V_{OL}	Low-level output voltage	I_{OUT} = 1.5 mA			0.1 × V_{CCIO}	V

Table 4–26. 1.5-V HSTL Class I Specifications						
Symbol	**Parameter**	**Conditions**	**Minimum**	**Typical**	**Maximum**	**Unit**
V_{CCIO}	Output supply voltage		1.4	1.5	1.6	V
V_{REF}	Input reference voltage		0.68	0.75	0.9	V
V_{TT}	Termination voltage		0.7	0.75	0.8	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = –8 mA *(3)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OL} = 8 mA *(3)*			0.4	V

Table 4–27. 1.5-V HSTL Class II Specifications						
Symbol	**Parameter**	**Conditions**	**Minimum**	**Typical**	**Maximum**	**Unit**
V_{CCIO}	Output supply voltage		1.4	1.5	1.6	V
V_{REF}	Input reference voltage		0.68	0.75	0.9	V
V_{TT}	Termination voltage		0.7	0.75	0.8	V
V_{IH} (DC)	DC high-level input voltage		V_{REF} + 0.1			V
V_{IL} (DC)	DC low-level input voltage		–0.3		V_{REF} – 0.1	V
V_{IH} (AC)	AC high-level input voltage		V_{REF} + 0.2			V
V_{IL} (AC)	AC low-level input voltage				V_{REF} – 0.2	V
V_{OH}	High-level output voltage	I_{OH} = –16 mA *(3)*	V_{CCIO} – 0.4			V
V_{OL}	Low-level output voltage	I_{OL} = 16 mA *(3)*			0.4	V

Table 4–41. M4K Block Internal Timing Microparameter Descriptions (Part 2 of 2)

Symbol	Parameter
$t_{M4KDATAAH}$	A port data hold time after clock
$t_{M4KADDRASU}$	A port address setup time before clock
$t_{M4KADDRAH}$	A port address hold time after clock
$t_{M4KDATABSU}$	B port data setup time before clock
$t_{M4KDATABH}$	B port data hold time after clock
$t_{M4KADDRBSU}$	B port address setup time before clock
$t_{M4KADDRBH}$	B port address hold time after clock
$t_{M4KDATACO1}$	Clock-to-output delay when using output registers
$t_{M4KDATACO2}$	Clock-to-output delay without output registers
$t_{M4KCLKHL}$	Register minimum clock high or low time. This is a limit on the min time for the clock on the registers in these blocks. The actual performance is dependent upon the internal point-to-point delays in the blocks and may give slower performance as shown inTable 4–36 on page 4–20 and as reported by the timing analyzer in the Quartus II software.
t_{M4KCLR}	Minimum clear pulse width

Table 4–42. M-RAM Block Internal Timing Microparameter Descriptions (Part 1 of 2)

Symbol	Parameter
t_{MRAMRC}	Synchronous read cycle time
t_{MRAMWC}	Synchronous write cycle time
$t_{MRAMWERESU}$	Write or read enable setup time before clock
$t_{MRAMWEREH}$	Write or read enable hold time after clock
$t_{MRAMCLKENSU}$	Clock enable setup time before clock
$t_{MRAMCLKENH}$	Clock enable hold time after clock
$t_{MRAMBESU}$	Byte enable setup time before clock
$t_{MRAMBEH}$	Byte enable hold time after clock
$t_{MRAMDATAASU}$	A port data setup time before clock
$t_{MRAMDATAAH}$	A port data hold time after clock
$t_{MRAMADDRASU}$	A port address setup time before clock
$t_{MRAMADDRAH}$	A port address hold time after clock
$t_{MRAMDATABSU}$	B port setup time before clock

Table 4–42. M-RAM Block Internal Timing Microparameter Descriptions (Part 2 of 2)

Symbol	Parameter
$t_{MRAMDATABH}$	B port hold time after clock
$t_{MRAMADDRBSU}$	B port address setup time before clock
$t_{MRAMADDRBH}$	B port address hold time after clock
$t_{MRAMDATACO1}$	Clock-to-output delay when using output registers
$t_{MRAMDATACO2}$	Clock-to-output delay without output registers
$t_{MRAMCLKHL}$	Register minimum clock high or low time. This is a limit on the min time for the clock on the registers in these blocks. The actual performance is dependent upon the internal point-to-point delays in the blocks and may give slower performance as shown in Table 4–36 on page 4–20 and as reported by the timing analyzer in the Quartus II software.
$t_{MRAMCLR}$	Minimum clear pulse width.

Table 4–53. Stratix Regional Clock External I/O Timing Parameters (Part 2 of 2) Notes (1), (2)	
Symbol	**Parameter**
t_{XZPLL}	Synchronous IOE output enable register to output pin disable delay using regional clock fed by Enhanced PLL with default phase setting
t_{ZXPLL}	Synchronous IOE output enable register to output pin enable delay using regional clock fed by Enhanced PLL with default phase setting

Notes to Table 4–53:
(1) These timing parameters are sample-tested only.
(2) These timing parameters are for column and row IOE pins. You should use the Quartus II software to verify the external timing for any pin.

Table 4–54 shows the external I/O timing parameters when using global clock networks.

Table 4–54. Stratix Global Clock External I/O Timing Parameters Notes (1), (2)	
Symbol	**Parameter**
t_{INSU}	Setup time for input or bidirectional pin using IOE input register with global clock fed by `CLK` pin
t_{INH}	Hold time for input or bidirectional pin using IOE input register with global clock fed by `CLK` pin
t_{OUTCO}	Clock-to-output delay output or bidirectional pin using IOE output register with global clock fed by `CLK` pin
$t_{INSUPLL}$	Setup time for input or bidirectional pin using IOE input register with global clock fed by Enhanced PLL with default phase setting
t_{INHPLL}	Hold time for input or bidirectional pin using IOE input register with global clock fed by Enhanced PLL with default phase setting
$t_{OUTCOPLL}$	Clock-to-output delay output or bidirectional pin using IOE output register with global clock Enhanced PLL with default phase setting
t_{XZPLL}	Synchronous IOE output enable register to output pin disable delay using global clock fed by Enhanced PLL with default phase setting
t_{ZXPLL}	Synchronous IOE output enable register to output pin enable delay using global clock fed by Enhanced PLL with default phase setting

Notes to Table 4–54:
(1) These timing parameters are sample-tested only.
(2) These timing parameters are for column and row IOE pins. You should use the Quartus II software to verify the external timing for any pin.

Tables 4–79 through 4–84 show the external timing parameters on column and row pins for EP1S40 devices.

Table 4–79. EP1S40 External I/O Timing on Column Pins Using Fast Regional Clock Networks

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.696		2.907		3.290		2.899		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.506	5.015	2.506	5.348	2.506	5.809	2.698	7.286	ns
t_{XZ}	2.446	4.889	2.446	5.216	2.446	5.685	2.638	7.171	ns
t_{ZX}	2.446	4.889	2.446	5.216	2.446	5.685	2.638	7.171	ns

Table 4–80. EP1S40 External I/O Timing on Column Pins Using Regional Clock Networks

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.413		2.581		2.914		2.938		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.668	5.254	2.668	5.628	2.668	6.132	2.869	7.307	ns
t_{XZ}	2.608	5.128	2.608	5.496	2.608	6.008	2.809	7.192	ns
t_{ZX}	2.608	5.128	2.608	5.496	2.608	6.008	2.809	7.192	ns
$t_{INSUPLL}$	1.385		1.376		1.609		1.837		ns
t_{INHPLL}	0.000		0.000		0.000		0.000		ns
$t_{OUTCOPLL}$	1.117	2.382	1.117	2.552	1.117	2.504	1.117	2.542	ns
t_{XZPLL}	1.057	2.256	1,057	2.420	1.057	2.380	1.057	2.427	ns
t_{ZXPLL}	1.057	2.256	1,057	2.420	1.057	2.380	1.057	2.427	ns

Tables 4–91 through 4–96 show the external timing parameters on column and row pins for EP1S80 devices.

Table 4–91. EP1S80 External I/O Timing on Column Pins Using Fast Regional Clock Networks Note (1)									
Parameter	**-5 Speed Grade**		**-6 Speed Grade**		**-7 Speed Grade**		**-8 Speed Grade**		**Unit**
	Min	**Max**	**Min**	**Max**	**Min**	**Max**	**Min**	**Max**	
t_{INSU}	2.328		2.528		2.900		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.422	4.830	2.422	5.169	2.422	5.633	NA	NA	ns
t_{XZ}	2.362	4.704	2.362	5.037	2.362	5.509	NA	NA	ns
t_{ZX}	2.362	4.704	2.362	5.037	2.362	5.509	NA	NA	ns

Table 4–92. EP1S80 External I/O Timing on Column Pins Using Regional Clock Networks Note (1)									
Parameter	**-5 Speed Grade**		**-6 Speed Grade**		**-7 Speed Grade**		**-8 Speed Grade**		**Unit**
	Min	**Max**	**Min**	**Max**	**Min**	**Max**	**Min**	**Max**	
t_{INSU}	1.760		1.912		2.194		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.761	5.398	2.761	5.785	2.761	6.339	NA	NA	ns
t_{XZ}	2.701	5.272	2.701	5.653	2.701	6.215	NA	NA	ns
t_{ZX}	2.701	5.272	2.701	5.653	2.701	6.215	NA	NA	ns
$t_{INSUPLL}$	0.462		0.606		0.785		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
$t_{OUTCOPLL}$	1.661	2.849	1.661	2.859	1.661	2.881	NA	NA	ns
t_{XZPLL}	1.601	2.723	1.601	2.727	1.601	2.757	NA	NA	ns
t_{ZXPLL}	1.601	2.723	1.601	2.727	1.601	2.757	NA	NA	ns

Figure 4–6 shows the case where four IOE registers are located in two different I/O banks.

Figure 4–6. I/O Skew Across Two I/O Banks

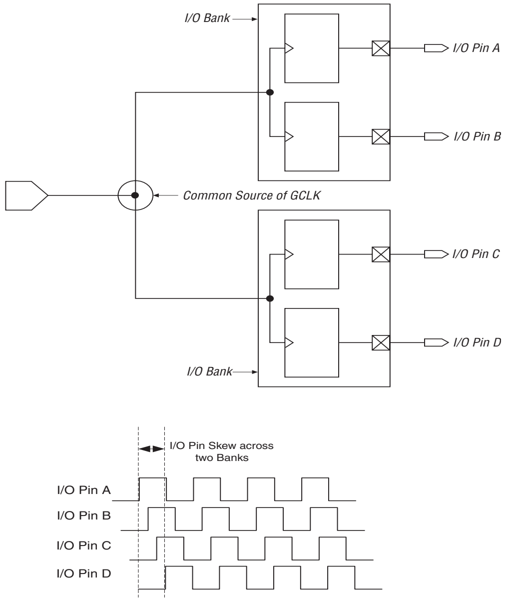


Table 4–97 defines the timing parameters used to define the timing for horizontal I/O pins (side banks 1, 2, 5, 6) and vertical I/O pins (top and bottom banks 3, 4, 7, 8). The timing parameters define the skew within an I/O bank, across two neighboring I/O banks on the same side of the device, across all horizontal I/O banks, across all vertical I/O banks, and the skew for the overall device.

Table 4–97. Output Pin Timing Skew Definitions (Part 1 of 2)

Symbol	Definition
t_{SB_HIO}	Row I/O (HIO) within one I/O bank *(1)*
t_{SB_VIO}	Column I/O (VIO) within one I/O bank *(1)*
t_{SS_HIO}	Row I/O (HIO) same side of the device, across two banks *(2)*
t_{SS_VIO}	Column I/O (VIO) same side of the device, across two banks *(2)*

Table 4–108. Stratix I/O Standard Output Delay Adders for Slow Slew Rate on Row Pins										
I/O Standard		-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA		1,571		1,650		1,650		1,650	ps
	4 mA		594		624		624		624	ps
	8 mA		208		218		218		218	ps
	12 mA		0		0		0		0	ps
3.3-V LVTTL	4 mA		1,571		1,650		1,650		1,650	ps
	8 mA		1,393		1,463		1,463		1,463	ps
	12 mA		596		626		626		626	ps
	16 mA		562		590		590		590	ps
2.5-V LVTTL	2 mA		2,562		2,690		2,690		2,690	ps
	8 mA		1,343		1,410		1,410		1,410	ps
	12 mA		864		907		907		907	ps
	16 mA		945		992		992		992	ps
1.8-V LVTTL	2 mA		6,306		6,621		6,621		6,621	ps
	8 mA		3,369		3,538		3,538		3,538	ps
	12 mA		2,932		3,079		3,079		3,079	ps
1.5-V LVTTL	2 mA		9,759		10,247		10,247		10,247	ps
	4 mA		6,830		7,172		7,172		7,172	ps
	8 mA		5,699		5,984		5,984		5,984	ps
GTL+			–333		–350		–350		–350	ps
CTT			591		621		621		621	ps
SSTL-3 Class I			267		280		280		280	ps
SSTL-3 Class II			–346		–363		–363		–363	ps
SSTL-2 Class I			481		505		505		505	ps
SSTL-2 Class II			–58		–61		–61		–61	ps
SSTL-18 Class I			2,207		2,317		2,317		2,317	ps
1.5-V HSTL Class I			1,966		2,064		2,064‘		2,064	ps
1.8-V HSTL Class I			1,208		1,268		1,460		1,720	ps

Table 4–119. Stratix Maximum Input Clock Rate for CLK[1, 3, 8, 10] Pins in Wire-Bond Packages (Part 2 of 2)				
I/O Standard	**-6 Speed Grade**	**-7 Speed Grade**	**-8 Speed Grade**	**Unit**
SSTL-18 Class I	350	300	300	MHz
SSTL-18 Class II	350	300	300	MHz
1.5-V HSTL Class I	350	300	300	MHz
1.8-V HSTL Class I	350	300	300	MHz
CTT	250	200	200	MHz
Differential 1.5-V HSTL C1	350	300	300	MHz
LVPECL *(1)*	645	622	622	MHz
PCML *(1)*	275	275	275	MHz
LVDS *(1)*	645	622	622	MHz
HyperTransport technology *(1)*	500	450	450	MHz

Note to Tables 4–114 through 4–119:
(1) These parameters are only available on row I/O pins.

Tables 4–120 through 4–123 show the maximum output clock rate for column and row pins in Stratix devices.

Table 4–120. Stratix Maximum Output Clock Rate for PLL[5, 6, 11, 12] Pins in Flip-Chip Packages (Part 1 of 2)					
I/O Standard	**-5 Speed Grade**	**-6 Speed Grade**	**-7 Speed Grade**	**-8 Speed Grade**	**Unit**
LVTTL	350	300	250	250	MHz
2.5 V	350	300	300	300	MHz
1.8 V	250	250	250	250	MHz
1.5 V	225	200	200	200	MHz
LVCMOS	350	300	250	250	MHz
GTL	200	167	125	125	MHz
GTL+	200	167	125	125	MHz
SSTL-3 Class I	200	167	167	133	MHz
SSTL-3 Class II	200	167	167	133	MHz
SSTL-2 Class I *(3)*	200	200	167	167	MHz
SSTL-2 Class I *(4)*	200	200	167	167	MHz
SSTL-2 Class I *(5)*	150	134	134	134	MHz

PLL Specifications

Tables 4–127 through 4–129 describe the Stratix device enhanced PLL specifications.

Table 4–127. Enhanced PLL Specifications for -5 Speed Grades (Part 1 of 2)

Symbol	Parameter	Min	Typ	Max	Unit
f_{IN}	Input clock frequency	3 *(1)*, *(2)*		684	MHz
f_{INPFD}	Input frequency to PFD	3		420	MHz
f_{INDUTY}	Input clock duty cycle	40		60	%
$f_{EINDUTY}$	External feedback clock input duty cycle	40		60	%
$t_{INJITTER}$	Input clock period jitter			±200 *(3)*	ps
$t_{EINJITTER}$	External feedback clock period jitter			±200 *(3)*	ps
t_{FCOMP}	External feedback clock compensation time *(4)*			6	ns
f_{OUT}	Output frequency for internal global or regional clock	0.3		500	MHz
f_{OUT_EXT}	Output frequency for external clock *(3)*	0.3		526	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%)	45		55	%
t_{JITTER}	Period jitter for external clock output *(6)*			±100 ps for >200-MHz `outclk` ±20 mUI for <200-MHz `outclk`	ps or mUI
$t_{CONFIG5,6}$	Time required to reconfigure the scan chains for PLLs 5 and 6			$289/f_{SCANCLK}$	
$t_{CONFIG11,12}$	Time required to reconfigure the scan chains for PLLs 11 and 12			$193/f_{SCANCLK}$	
$t_{SCANCLK}$	`scanclk` frequency *(5)*			22	MHz
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays) *(7)*			100	µs
t_{LOCK}	Time required to lock from end of device configuration	10		400	µs
f_{VCO}	PLL internal VCO operating range	300		800 *(8)*	MHz
t_{LSKEW}	Clock skew between two external clock outputs driven by the same counter		±50		ps